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Applicant(s)/Patent under Reexamination

10/792,074

YERBY ET AL.
Art Unit

Examiner

PHILIPPE S. DERAKSHANI

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SEARCHED .					
Class	Subclass	Date	Examiner		
222	402.11 402.13 153.13 153.11	12/18/2007	PD		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
222	153.13				
222	402.11	12/18/2007	PD		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
,	DATE	EXMR		
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